

Search Notes

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TAN X. DINH

Applicant(s)/Patent under
Reexamination

YAMASHITA, SATOSHI

Art Unit

2627

SEARCHED

Class	Subclass	Date	Examiner

INTERFERENCE SEARCHED

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**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST (see search history printout)	2/13/2007	T.D